

C1812X334M1RACTU

Aliases (C1812X334M1RAC7800) SMD Comm X7R Flex, Ceramic, 0.33 uF, 20%, 100 VDC, X7R, SMD, MLCC, FT-CAP, Temperature Stable, 1812, 2.3 mm



| General Information | |
|--------------------------|--|
| Series | SMD Comm X7R Flex |
| Style | SMD Chip |
| Description | SMD, MLCC, FT-CAP, Temperature Stable |
| Features | FT-CAP, Temperature Stable |
| RoHS | Yes |
| Termination | Flexible Termination |
| Marking | No |
| AEC-Q200 | No |
| Typical Component Weight | 95 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|------------|------------------|
| Chip Size | 1812 |
| L | 4.5mm +/-0.4mm |
| W | 3.2mm +/-0.3mm |
| Т | 1.55mm +/-0.10mm |
| S | 2.3mm MIN |
| В | 0.7mm +/-0.35mm |
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| В | 0.7mm +/-0.35mm |
|--------------------------|--------------------------|
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| Packaging Specifications | |
| Packaging | T&R, 180mm, Plastic Tape |
| Packaging Quantity | 1000 |

| Specifications | |
|--|--|
| Capacitance | 0.33 uF |
| Measurement Condition | 1 kHz 1.0Vrms |
| Tolerance | 20% |
| Voltage DC | 100 VDC |
| Dielectric Withstanding Voltage | 250 VDC |
| Temperature Range | -55/+125°C |
| Temp. Coefficient | X7R |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 15%, 1kHz 1.0Vrms |
| Dissipation Factor | 2.5% 1 kHz 1.0Vrms |
| Aging Rate | 3% Loss/Decade Hour: Referee Time is 1000 Hours |
| Insulation Resistance | 3.0303 GOhms |

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